

Progress in Materials Synthesis and Processing of Barium Titanium Oxide (BaTiO₃) and Barium Strontium Titanium Oxide (BaTiSrO₃) Films for Uncooled Infrared (IR) Detector Applications

by Wendy L. Sarney, Kimberley A. Olver, John W. Little Frank E. Livingston, Krisztian Niesz, and Daniel E. Morse

ARL-TR-5853 December 2011

NOTICES

Disclaimers

The findings in this report are not to be construed as an official Department of the Army position unless so designated by other authorized documents.

Citation of manufacturer's or trade names does not constitute an official endorsement or approval of the use thereof.

Destroy this report when it is no longer needed. Do not return it to the originator.

Army Research Laboratory

Adelphi, MD 20783-1197

ARL-TR-5853 December 2011

Progress in Materials Synthesis and Processing of Barium Titanium Oxide (BaTiO₃) and Barium Strontium Titanium Oxide (BaTiSrO₃) Films for Uncooled Infrared (IR) Detector Applications

Wendy L. Sarney, Kimberley A. Olver, and John W. Little Sensors and Electron Devices Directorate, ARL

Frank E. Livingston
The Aerospace Corporation

and

Krisztian Niesz and Daniel E. Morse Institute for Collaborative Biotechnologies University of California Santa Barbara

Approved for public release; distribution unlimited.

REPORT DOCUMENTATION PAGE

Form Approved OMB No. 0704-0188

Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing the burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number

PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS.

1. REPORT DATE (DD-MM-YYYY)	2. REPORT TYPE	3. DATES COVERED (From - To)				
December 2011 Final						
4. TITLE AND SUBTITLE		5a. CONTRACT NUMBER				
	s and Processing of Barium Titanium Oxide					
(BaTiO ₃) and Barium Strontium Uncooled Infrared (IR) Detector	n Titanium Oxide (BaTiSrO ₃) Films for or Applications	5b. GRANT NUMBER				
		5c. PROGRAM ELEMENT NUMBER				
6. AUTHOR(S) Wandy I. Sarnay Kimbarlay	A. Olver, John W. Little, Frank E. Livingston,	5d. PROJECT NUMBER				
Krisztian Niesz, and Daniel E.						
,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		5e. TASK NUMBER				
		5f. WORK UNIT NUMBER				
7. PERFORMING ORGANIZATION NA		8. PERFORMING ORGANIZATION REPORT NUMBER				
U.S. Army Research Laborator ATTN: RDRL-SEE-I 2800 Powder Mill Road Adelphi, MD 20783-1197	у	ARL-TR-5853				
9. SPONSORING/MONITORING AGEN	ICY NAME(S) AND ADDRESS(ES)	10. SPONSOR/MONITOR'S ACRONYM(S)				
		11. SPONSOR/MONITOR'S REPORT NUMBER(S)				
12 DISTRIBUTION/AVAILABILITY ST	A TENEDIT	•				

12. DISTRIBUTION/AVAILABILITY STATEMENT

Approved for public release; distribution unlimited.

13. SUPPLEMENTARY NOTES

14. ABSTRACT

This report describes the highlights and summary of the year 2, quarter four (Y2Q4) progress for the 6.2 project "Improved Sensitivity Low-Cost Uncooled IR Detector Focal-Plane Arrays." This work occurred during the January 2010–May 2010 time period. The program goals for Y2Q4 corresponded to the continued expansion of our barium titanium oxide (BaTiO₃) nanomaterial synthesis capabilities and deposition methods; laser-induced pyroelectric phase conversion studies and nanoscale characterization of the pyroelectric activation process; and fabrication of infrared (IR) test heterostructures for pyroelectrical analysis, along with the development of a technique for generating the requisite IR absorbing layer.

15. SUBJECT TERMS

Uncooled infrared

16. SECURITY CLASSIFICATION OF:			17. LIMITATION 18. NUMBER OF OF ABSTRACT PAGES		19a. NAME OF RESPONSIBLE PERSON Wendy L. Sarney		
a. REPORT	b. ABSTRACT	c. THIS PAGE	UU	28	19b. TELEPHONE NUMBER (Include area code)		
Unclassified	Unclassified	Unclassified	00	20	(301) 394-5761		

Standard Form 298 (Rev. 8/98) Prescribed by ANSI Std. Z39.18

Contents

Lis	t of F	igures	iv
Lis	t of T	Tables Tables	v
Ac	know	ledgments	vi
1.	Intr	oduction	1
2.	Prog	gress by the Aerospace Corporation (Aerospace)	2
	2.1	Laser-scripted Direct-write Processing of BaTiO ₃ and BaSrTiO ₃ Thin Films for Electrical Analysis	
		2.1.2 Laser-induced Pixelation/Pyroelectric Activation	4
	2.2	Nanoscale Ferroelectric Characterization of Laser-induced Pyroelectric Activation in ICB Perovskite Thin Films	6
	2.3	Measurement of Optical Band Gap Energies for CeO ₂ -doped Perovskite Thin Films	s9
3.	Prog	gress by the Institute for Collaborative Biotechnologies (ICB)	11
	3.1	BaTiO ₃ and BaSrTiO ₃ Sample Preparation with Varying Compositions and Thickness; Surface Stabilization Studies with PVP	11
4.	Pro	gress by ARL	11
	4.1	Nanostructured IR Absorbing Layer Development	11
	4.2	Frequency and Temperature Dependent Capacitance/Conductance Measurements	13
	4.3	Nanoscale Characterization of BSTO Particles	14
5.	Plar	ns and Goals for Year 3, Quarter 1	15
6.	Met	rics for Year 2 Quarter 4	16
	6.1	Publications	16
	6.2	Conferences and Symposia	16
Lis	t of S	ymbols, Abbreviations, and Acronyms	17
Dis	tribu	tion List	19

List of Figures

Figure 1. Project schedule	1
Figure 2. CAD illustration of a single 8x8 sub-array comprising 64 individual pixels, where the pixel dimensions are 100 μm x 100 μm with a center-to-center spacing of 200 μm. Each 8x8 pixel sub-array is enclosed in a 2.2 mm x 2.20 mm frame for visual reference and deposition mask alignment.	3
Figure 3. CAD illustration of a 4x4-(8x8) master array comprising 1024 pixels and sixteen 8x8 pixel sub-arrays.	4
Figure 4. Low (left) and high (right) magnification photomicrographs acquired following the laserscripted pixelation of $4x4$ -($8x8$) arrays on a Kapton film on quartz at $\lambda = 355$ nm.	5
Figure 5. Low (left) and high (right) magnification photomicrographs of an individual $8x8$ pixel array acquired following the laser-scripted patterning of a Kapton film at $\lambda = 355$ nm. The inset (upper right) shows a single $100 \mu m \times 100 \mu m$ pixel element.	5
Figure 6. Low (left) and high (right) magnification photomicrographs acquired following the laser scripted pixelation and pyroelectric activation of $4x4$ -($8x8$) arrays on a pure, undoped BaTiO ₃ thin-film at $\lambda = 355$ nm. The inset (upper right) shows a single 100 μ m x 100 μ m pixel element.	6
Figure 7. PFM concept where the mechanical response of the thin film is measured during local high frequency excitation by the AFM probe tip. The topography and piezoresponse profiles can be simultaneously acquired and decoupled to provide surface roughness and ferroelectric phase contrast information.	7
Figure 8. PFM images (in-plane polarization) of BaTiO ₃ thin films that were acquired (a) prior to laser exposure and (b) following laser-scripted patterning and pyroelectric phase conversion at $\lambda = 355$ nm. The image sizes are 5 μ m x 5 μ m.	8
Figure 9. PFM images (out-of-plane polarization) of BaTiO ₃ thin films that were acquired (a) prior to laser exposure and (b) following laser-scripted patterning and pyroelectric phase conversion at $\lambda = 355$ nm. The image sizes are 5 μ m x 5 μ m. (c) High magnification PFM image showing typical ferroelectric domain sizes of 50–500 nm	8
Figure 10. Optical transmission spectra measured for pure and CeO ₂ -doped BaTiO ₃ and BaSrTiO ₃ films with thicknesses of 550 nm. The inset shows the cerium (Ce ⁴⁺) absorption spectrum.	10
Figure 11. The absorption (relative to a bare Si wafer) at different wavelengths as a function of the etch time for the currently-developed IR absorption layer.	12
Figure 12. Transmission electron microscope (TEM) images of as-prepared BaTi nanoparticles stabilized with PVP.	13
Figure 13. Capacitance test structure.	14
Figure 14. SEM image of an 8x8 array (one column is for ground plane contact) of 100 x 100 µm Ti/Pt-SiO ₂ capacitors.	15

T	• 4	e			
	ist	Λt	ിറ	h	AC
	/I.S.I.	.,,	10	.,,	

Acknowledgments

We acknowledge support by the Institute for Collaborative Biotechnologies through grant DAAD19-03-D-0004 from the U.S. Army Research Office and The Aerospace Corporation Independent Research and Development (IR&D) Program and the Product and Development Program (PDP).

1. Introduction

This report describes the highlights and summary of the year 2, quarter four (Y2Q4) progress for the 6.2 project "Improved Sensitivity Low-Cost Uncooled IR Detector Focal-Plane Arrays." This work occurred during the January 2010–May 2010 time period. The project schedule for year 2 is summarized in figure 1.

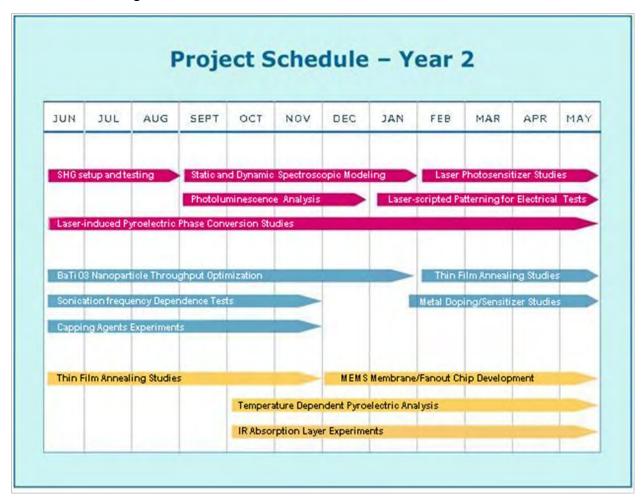


Figure 1. Project schedule.

The program goals for Y2Q4 corresponded to the continued expansion of our barium titanium oxide (BaTiO₃) nanomaterial synthesis capabilities and deposition methods; laser-induced pyroelectric phase conversion studies and nanoscale characterization of the pyroelectric activation process; and fabrication of infrared (IR) test heterostructures for pyroelectrical analysis, along with the development of a technique for generating the requisite IR absorbing layer. Respective team highlights include the following:

- Aerospace: This team conducted laser-scripted pixelation and pyroelectric activation of 8x8 pixel subarrays and 4x4-(8x8) pixel master arrays on Institute for Collaborative Biotechnologies (ICB) perovskite thin-film test structures for electrical characterization by the U.S. Army Research Laboratory (ARL). We successfully implemented piezoresponse force microscopy (PFM) techniques for the nanoscale ferroelectric analysis of the laserinduced pyroelectric phase activation process in perovskite thin films. Efforts also focused on the optical analysis and laser scripted processing of cerium (Ce)-doped perovskite nanoparticle thin films for enhanced laser-induced phase conversion efficiency.
- *ICB*: This team extended the bio-inspired vapor diffusion catalytic methods to include the synthesis, functionalization and deposition of perovskite nanoparticle (BaTiO₃, Ba_{1-x}Sr_xTiO₃) thin films comprising different compositions and thickness, along with the inclusion of Ce-dopant for enhanced ultraviolet (UV) absorption and improved laser-induced pyroelectric phase activation. Surface stabilization of the BaTiO₃ nanoparticles was also achieved using polyvinylpyrrolidone (PVP), which was found to facilitate the formation of stable colloids of BaTiO₃ and thereby mitigate the need for additional predeposition dispersion steps with carboxylic acids.
- *ARL:* This team continued with the development and refinement of the nanostructured IR absorbing layer, including optical absorption analysis of the nanostructures as a function of etch time. We established an electrical measurement system for frequency and temperature dependent capacitance/conductance measurements on native and laser-processed perovskite thin films, and fabricated 8x8 standard reference (titanium platinum [Ti/Pt]-silicon dioxide [SiO₂]) capacitor structures for baseline electrical testing. High resolution nanoscale characterization of re-dispersed barium strontium titanium oxide (Ba_{1-x}Sr_xTiO₃ or BSTO) nanoparticles was also accomplished.

All project teams have accomplished their respective planned milestones for Y2Q4. Highlights of the major activities are provided in sections 2 through 4.

2. Progress by the Aerospace Corporation (Aerospace)

2.1 Laser-scripted Direct-write Processing of BaTiO₃ and BaSrTiO₃ Thin Films for Electrical Analysis

2.1.1 CAD-CAM Patterning of Pixel Arrays

Our recent efforts in year 2 have focused on the digitally scripted laser genotype direct-write processing of ICB-provided BaTiO₃ and BaSrTiO₃ thin films, with particular emphasis on the systematic correlation of the laser processing parameters with the (pyro)electrical properties and IR responsiveness of the perovskite test structures. Based on the existing and preferred ARL mask geometries for metal contact deposition, our recent studies include laser processing

exposure patterns that comprise 8x8 pixel sub-arrays and 4x4-(8x8) pixel master arrays, as depicted in figures 2 and 3. Figure 2 shows a computer-assisted design (CAD) representation of a single 8x8 sub-array comprising 64 individual pixels, where the pixel dimensions are 100 μ m x 100 μ m with a lateral spacing of 100 μ m and a center-to-center spacing of 200 μ m. Each pixel is laser patterned using a sequential line fill with a lateral step-over that is comparable to the laser spot size (1–3 μ m). Equivalent laser processing parameters—in the form of laser pulse "scripts" that are "linked" on a per spot basis to the tool path geometry in Cartesian space and contain specific information on laser pulse energy, polarization, wavelength, etc.—are applied to a series of four pixels so that 16 sets of laser processing parameters or "scripts" are administered to each 64 pixel set.

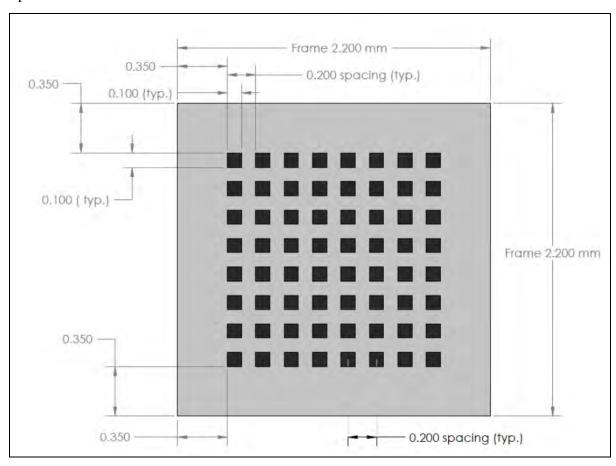


Figure 2. CAD illustration of a single 8x8 sub-array comprising 64 individual pixels, where the pixel dimensions are $100 \mu m \times 100 \mu m$ with a center-to-center spacing of $200 \mu m$. Each 8x8 pixel sub-array is enclosed in a $2.2 mm \times 2.20 mm$ frame for visual reference and deposition mask alignment.

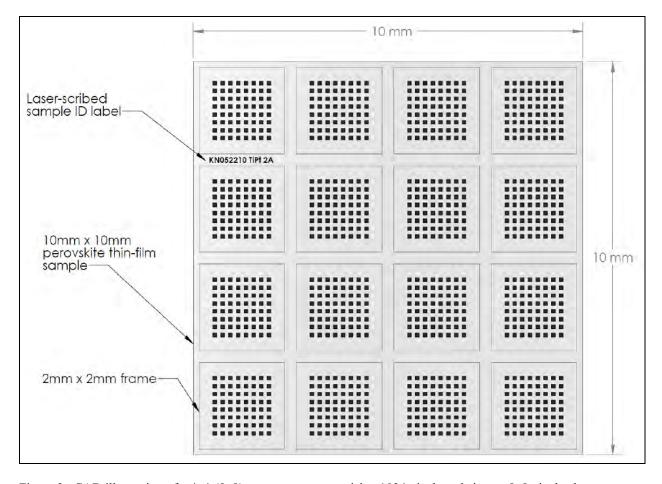


Figure 3. CAD illustration of a 4x4-(8x8) master array comprising 1024 pixels and sixteen 8x8 pixel sub-arrays.

Figure 3 displays a CAD illustration of a 4x4 master array of the 8x8 sub-arrays patterned on a standard 10 mm x 10 mm substrate, where the 16 8x8 pixel sub-arrays are processed using equivalent laser parameters and correspond to a total of 1024 laser-pixelated regions per sample. This laser-scripted redundancy can be implemented to assess the reproducibility of pyroelectric phase activation and film homogeneity across the entire spin-cast perovskite sample.

For visual reference and to facilitate the mask alignment procedure for metal contact deposition by ARL, each of the 16 8x8 pixel sub-arrays is enclosed by a 2.200 µm x 2.200 µm frame with a 100 m width. The frames are created using laser-controlled ablative patterning and the laser power is set to gently ablate or desorb the perovskite thin film without damage to the underlying Ti/Pt:silicon (Si) substrate. The distance from the outer edge of each of the four frame corners to the nearest corners of the four adjacent pixels (i.e., pixels 1, 8, 57, and 64) is 350 µm.

2.1.2 Laser-induced Pixelation/Pyroelectric Activation

Preliminary laser-scripted patterning and pixel array fabrication experiments were performed on organic polyimide thin films, such as KaptonTM. These polymer-based films retain a very low thermal ablation threshold and are therefore useful in verifying high precision control of incident

photon flux and revealing the possible existence of excessive heat loading effects and residual thin-film damage. Additionally, low fluence laser exposure patterning of the organic thin films can be used to compare the laser-scripted pattern dimensions with the CAD-computer aided manufacturing (CAM) geometries and help elucidate any deviations or discrepancies.

Figures 4 and 5 show a series of low and high magnification photomicrographs of composite 4x4-(8x8) pixel arrays and 8x8 pixel sub-arrays that were laser patterned on a Kapton thin film. The 1024 individual pixel elements, along with the sub-array frames and sample identification label, were fabricated using laser irradiation at λ =355 nm, a pulse repetition rate of 80 MHz, and a pulse duration of 10 ps. The per-pulse fluence employed for pixelation and frame/ID were E=0.88 mJ·cm⁻² and E=2.00 mJ·cm⁻², respectively. A non-contact white light optical profilometer was used to measure the laser-fabricated pixels, lateral pixel spacing distances, and frame dimensions. The standard deviation between the laser-scripted pattern dimensions and the user-defined CAD geometries was measured to be less than 0.05% and is consistent with the nominal resolution and repeatability of the XYZ air bearing translation stage encoders of 40 nm.

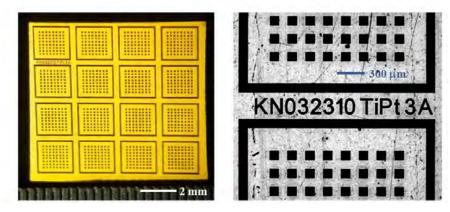


Figure 4. Low (left) and high (right) magnification photomicrographs acquired following the laserscripted pixelation of 4x4-(8x8) arrays on a Kapton film on quartz at $\lambda = 355$ nm.

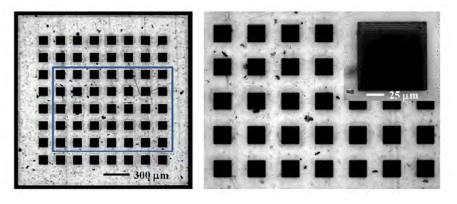
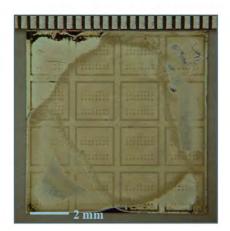


Figure 5. Low (left) and high (right) magnification photomicrographs of an individual 8x8 pixel array acquired following the laser-scripted patterning of a Kapton film at $\lambda=355$ nm. The inset (upper right) shows a single 100 μm x 100 μm pixel element.

During the fourth quarter, digitally scripted laser genotype processing techniques were also implemented to create patterned and pyroelectrically active pixel arrays on ICB undoped and CeO₂-doped BaTiO₃ and Ba_{1-x}Sr_xTiO₃ thin films deposited on Ti/Pt:Si substrates. Laser-scripted direct-write laser pulse modulation was used to convert pixelated regions (100 µm x 100 µm) of the perovskite thin-films from the pyroelectrically inactive cubic polymorph to the pyroelectrically active tetragonal polymorph. Figure 6 shows several photomicrographs of an undoped BaTiO₃ thin film sample following laser pixelation and pyroelectric phase activation at $\lambda = 355$ nm (80 MHz, 10 ps full width at half maximum [FWHM]). The BaTiO₃:Ti/Pt:Si sample was 10 mm x 10 mm in size, and contained sixteen 8x8 pixel sub-arrays for a total of 1024 laser-pixelated regions. The pixelated regions were patterned using 16 sets of laser processing parameters—i.e., genotype laser pulse "scripts"—for each 8x8 pixel sub-array. The large laser processing parameter set will help to optimize the pyroelectric phase activation protocol and facilitate the correlation of the laser processing conditions with the electrical properties of the pixel domains. The variation in pixel contrast uniformity and darkness arise from the diverse set of laser processing pulse scripts that were implemented for patterning, and do not correspond to inhomogeneities or variegations in the perovskite thin film.

A set of laser-pixelated BaTiO₃:Ti/Pt:Si and BaTiO₃-CeO₂:Ti/Pt:Si samples have been shipped to ARL, and electrical analysis and pyroelectrical responsiveness tests are now underway.



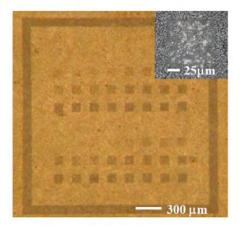


Figure 6. Low (left) and high (right) magnification photomicrographs acquired following the laser scripted pixelation and pyroelectric activation of 4x4-(8x8) arrays on a pure, undoped BaTiO₃ thin-film at $\lambda = 355$ nm. The inset (upper right) shows a single 100 μ m x 100 μ m pixel element.

2.2 Nanoscale Ferroelectric Characterization of Laser-induced Pyroelectric Activation in ICB Perovskite Thin Films

Our fourth quarter efforts for year 2 have also focused on the nanoscale characterization of the ferroelectric properties of laser-processed barium titanate thin films. We are continuing to develop the use of scanning PFM techniques for nanoscale analysis of the laser-induced BaTiO₃ cubic-to-tetragonal pyroelectric phase transformation, along with an assessment of the relative

magnitudes of the ferroelectric phase contrasts of the respective nonferroelectric (nFE)/ ferroelectric (FE) domains. As noted in our prior quarterly reports, PFM permits direct imaging of ferroelectric domain structures with nanometer-scale resolution (~3–10 nm) and is ideally suited for post-laser-processing examination of the perovskite thin films due to its relative insensitivity to topography and ease of implementation. We have successfully augmented and tailored our traditional atomic force microscopy (AFM) instrument for PFM operation, where the mechanical response of the sample is measured during local electrical excitation by the AFM probe tip. A modulated AC voltage is applied between the underlying Ti/Pt:Si substrate and conductive AFM/PFM tip during contact mode scanning. Using lock-in amplifier techniques, the local electromechanical displacement can be decoupled from the topographical displacement via the phase shift between the rapidly oscillating ac field and the slow cantilever displacement feedback (figure 7). The static cantilever deflection corresponds to the surface profile variations and topography, while the modulated cantilever oscillations are related to the piezoresponse of the perovskite sample.

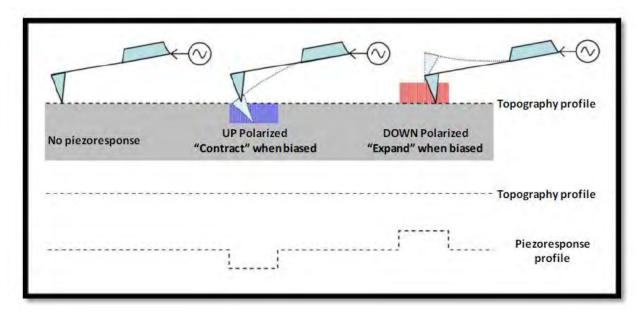


Figure 7. PFM concept where the mechanical response of the thin film is measured during local high frequency excitation by the AFM probe tip. The topography and piezoresponse profiles can be simultaneously acquired and decoupled to provide surface roughness and ferroelectric phase contrast information.

Figure 8a displays a PFM image of a BaTiO₃ thin-film sample that was acquired prior to laser-scripted exposure at $\lambda = 355$ nm and shows no in-plane (polarization parallel to sample surface) ferroelectric phase contrast for the as-received cubic crystalline BaTiO₃ thin film. Following laser-scripted exposure at =355 nm ($\sim 1 \times 10^6$ pulses, per-pulse fluence = 2.5 mJ·cm⁻²), the PFM results in figure 8b reveal appreciable ferroelectric phase contrast and confirm successful pyroelectric conversion to the tetragonal phase. Figures 9a and 9b show similar PFM contrast behavior for the unexposed and laser-processed BaTiO₃ thin film, where the measured

piezoresponse signals correspond to polarization dipoles that are aligned perpendicular to the sample surface. The laser-structured and pyroelectrically activated regions appear uniform and retain ferroelectric domain sizes of \sim 50–500 nm.

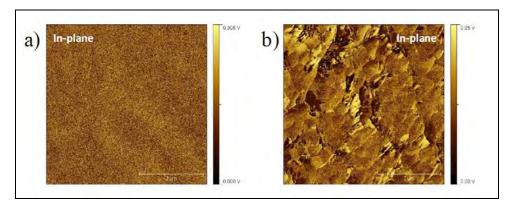


Figure 8. PFM images (in-plane polarization) of BaTiO₃ thin films that were acquired (a) prior to laser exposure and (b) following laser-scripted patterning and pyroelectric phase conversion at $\lambda = 355$ nm. The image sizes are 5 μ m x 5 μ m.

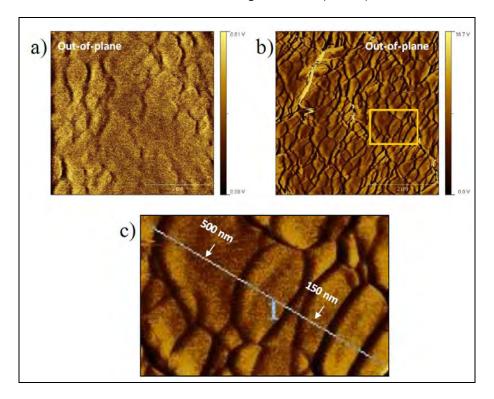


Figure 9. PFM images (out-of-plane polarization) of BaTiO₃ thin films that were acquired (a) prior to laser exposure and (b) following laser-scripted patterning and pyroelectric phase conversion at $\lambda = 355$ nm. The image sizes are 5 μ m x 5 μ m. (c) High magnification PFM image showing typical ferroelectric domain sizes of 50–500 nm.

2.3 Measurement of Optical Band Gap Energies for CeO₂-doped Perovskite Thin Films

Expanding upon our prior detailed studies concerning the influence of perovskite film thickness on the intrinsic optical bandgap energies of the nanostructured films, we are now examining the optical properties of *doped* perovskite nanoparticle thin films. The intent is to incorporate the appropriate photo-active constituents (e.g., CeO₂) into the perovskite nanoparticles to enhance the UV absorption in the native thin films and thereby improve the laser-induced pyroelectric phase conversion efficiency and reduce the incident laser energy required for pyroelectric activation. The prudent selection of dopant type and concentration will also facilitate the fine-tuning of the electrical properties of the perovskite thin films and may enable a broader range of pyroelectric responsiveness.

Our prior optical transmission studies indicated that for the thicker micron-sized BaTiO $_3$ films (>1 µm), inter-band transitions occur at wavelengths of λ <450–500 nm, and the transmission falls rapidly to less than 10% at wavelengths of λ <400 nm. In contrast, inter-band transitions occur at wavelengths of λ <300 nm for the thinner 200–500 nm-thick films, and the 10% cut-off occurs at UV wavelengths of <260 nm. Consequently, the absolute bandgap energies for the thinner and functionalized BaTiO $_3$ films are significantly *blue-shifted* compared with the thicker micrometer scale films. The calculated bandgap energies displayed the following trend with film thicknesses denoted in parentheses: E=3.27±0.4 eV (3–5 µm), 3.84±0.2 eV (0.5–1 µm), 3.95±0.1 eV (300–500 nm), and 4.12±0.05 eV (200–300 nm). The film-thickness dependent behavior of the bandgap energy severely impacts the selection of the appropriate laser processing wavelengths and other laser parameters that are requisites for efficient laser energy-material coupling and optimal pyroelectric phase conversion. For low-cost rapid prototype manufacture of the IR sensor components, the use of a readily available commercial solid-state laser system is preferred.

Accordingly, and with our ICB collaborators, we have explored the effect of incorporating CeO₂ into the perovskite nanoparticles during synthesis as a means to *red-shift* the absorption band edge of the nanostructured films, thereby lowering the optical bandgap energies and reducing the total incident laser irradiation required for complete pyroelectric phase transformation. Figure 9 shows the optical transmission spectra that were measured for pure BaTiO₃ and CeO₂-doped (0.03 wt%) BaTiO₃ thin films. The BaTiO₃ samples correspond to 1-layer spin coatings with a nominal film thickness of ~550 nm. The optical results presented in figure 10 are encouraging, and reveal that low impurity doping with CeO₂ can be used to reduce the UV transmission for <350 nm and induce a red-shift in the band gap energy. For example, the bandgap energy and 10% T cut-off wavelength for the pure undoped 550-nm-thick BaTiO₃ films were measured to be E=4.02±0.05 eV and =264.5 nm, respectively. However, the bandgap energy has been reduced to E=3.87±0.05 eV and the 10% T cut-off has been shifted to a longer wavelength of $\lambda = 300$ nm for the CeO₂-doped BaTiO₃ film of comparable thickness. The optical results for the pure and CeO₂-doped BaTiO₃ and BaSrTiO₃ films are summarized in table 1.

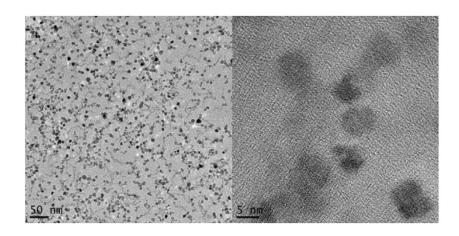


Figure 10. Optical transmission spectra measured for pure and CeO₂-doped BaTiO₃ and BaSrTiO₃ films with thicknesses of 550 nm. The inset shows the cerium (Ce⁴⁺) absorption spectrum.

Table 1. Summary of the optical results for the pure and CeO₂-doped BaTiO₃ and BaSrTiO₃ films.

Number of Spin Coat Layers	Film Thickness (nm)	Band Gap Energy (eV)/10% T Cut-off (nm)							
		BaTiO₃		BaTiO₃-CeO₂		BaSrTiO₃		BaSrTiO3-CeO2	
1	550	4.02	264.5	3.87	300.0	3.85	298.0	3.70	318.5
2	1100	3.91	280.0	3.78	315.0				
3	1440	3.80	296.5	3.73	323.5				

The inset in figure 10 shows the absorption spectrum that is associated with the Ce chromophore, and was derived from the difference between the CeO_2 -doped and undoped perovskite thin-film. The primary spectral feature is an absorption peak located near =230–235 nm and corresponds to the Ce^{4+} oxidation state of Ce. A broad featureless absorption is also observed and extends beyond 250 nm. There is a rapid absorption fall-off for wavelengths >300 nm, and this behavior is likely responsible for the negligible change in absorption characteristics for the thicker (>1 μ m) CeO_2 -doped BaSrTiO₃ films.

3. Progress by the Institute for Collaborative Biotechnologies (ICB)

3.1 BaTiO₃ and BaSrTiO₃ Sample Preparation with Varying Compositions and Thickness; Surface Stabilization Studies with PVP

The ICB efforts focused on three critical areas regarding perovskite sample synthesis and thinfilm preparation:

- Based on our previous experiences, samples with different compositions (BaTiO₃, Ba_{1-x}Sr_xTiO₃), with and without using additional Ce dopant were synthesized, functionalized with oleic acid and deposited from colloidal suspensions onto different types of substrates (quartz, Pt/Ti:Si). The depositions were carried out by layer-by-layer spinning using different numbers of deposition/annealing cycles to vary the perovskite film thickness. The samples were then sent to our collaborating partners at Aerospace and ARL for further investigations.
- Comprehensive sets of pure (undoped) and CeO₂-doped (0.03 wt%) BaTiO₃ and Ba_{1-x}Sr_xTiO₃ thin films were prepared and sent to Aerospace for laser-scripted processing and pixelation/activation studies, as well as optical analysis. These samples included systematic variation of the film thickness from 550 nm (1-layer spin coat) to 1440 nm (3-layer spin coat). BaTiO₃ and Ba_{1-x}Sr_xTiO₃ samples—in their nascent nanoparticle form—were synthesized and sent to ARL for thin-film test structure fabrication and electrical characterization.
- Experiments were conducted using PVP as surface stabilizing agent to form BaTi nanoparticles as stable colloids. Performing the synthesis this way the additional stabilizing step with oleic acid before depositions could be avoided. Adding PVP to the BaTi double alkoxide molecules dissolved in butanol (2:1 molar ratio of PVP-monolayer to BaTi-precipitate) indeed resulted in the formation of BaTiO₃ nanocrystals stable against aggregation (see figure 10).

4. Progress by ARL

4.1 Nanostructured IR Absorbing Layer Development

As explained in the prior quarter's report, thermal detectors require a layer similar to a thin coating of black paint that absorbs a wide range of wavelengths and heats up. The heat is transferred to the BT layer and the pyroelectric voltage is generated. We are developing a low-cost technique that is temperature-compatible with the bio-inspired BaTiO₃ films and with readout integrated circuit (ROIC) technology. The details of the process were given in the

previous quarterly report, but the main features of the technique involve forming nanoparticles of metal (e.g., gold [Au]) on an evaporated Si film and subsequently etching the Si with a dry etch. The Au particles mask the surface resulting in nanopilars of Si that have been shown to trap and absorb light strongly. We formed the particles on a Si wafer by heating a 5-nm evaporated Au film to 350 °C and etched pieces in a carbon tetrafluoride (CF₄) plasma for various times.

Figure 11 shows the absorption (relative to a bare Si wafer) at different wavelengths as a function of the etch time. Note that for this first set of samples, the highest absorption was obtained for a 20 s and was peaked at 1.5 μ m wavelength. This wavelength is ideal for enhancing the near IR photoresponse of solar cells, and we are transitioning this technology to our quantum dot solar cell program.

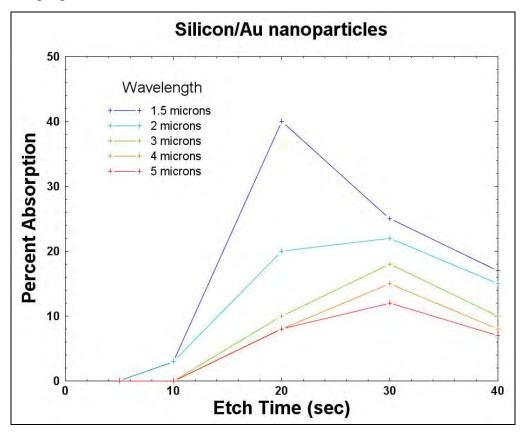


Figure 11. The absorption (relative to a bare Si wafer) at different wavelengths as a function of the etch time for the currently-developed IR absorption layer.

We are modifying the nanostructure to push the wavelength into the thermal imaging part of the spectrum (3–12 μ m) and maximize the absorption strength. A new set of samples is being prepared with larger scale and deeper nanostructures and the results will be given in a subsequent report.

4.2 Frequency and Temperature Dependent Capacitance/Conductance Measurements

We have begun establishing a measurement system that will characterize the temperature and frequency dependence of the capacitance/conductance of the BaTiO₃ films (in order to determine the pyroelectric properties of the films). A Hewlett Packard 4280A precision fixed frequency (1 MHz) capacitance meter and a variable frequency (1 Hz–1 MHz) function generator/quadrature lock-in amplifier is used to measure the capacitance/conductance of our test samples. The system has been calibrated with a precision capacitance bridge. A variable temperature sample mount will be added soon.

Figures 12 and 13 show an 8 x 8 array (one column is for ground plane contact) of Ti/Pt–SiO₂ capacitors (100 x 100 microns) that we fabricated as a standard reference for the measurement system (this test structure has a known capacitance). These samples have the same configuration as the laser-modified BT films.

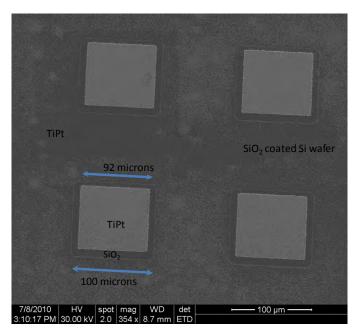


Figure 12. Transmission electron microscope (TEM) images of as-prepared BaTi nanoparticles stabilized with PVP.

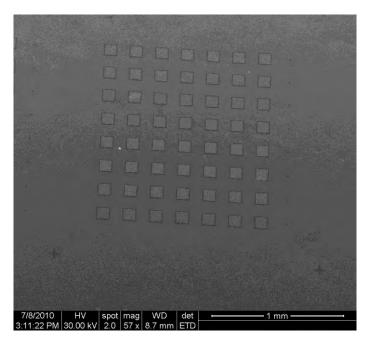


Figure 13. Capacitance test structure.

4.3 Nanoscale Characterization of BSTO Particles

In this quarter, the ICB sent vials of BSTO nanoparticles to ARL. As detailed in the prior report, BSTO has several desirable properties for both IR detector and laser processing applications. These include a relatively large dielectric constant, good pyroelectric response near room temperature, low dielectric loss and leakage current, and phase transition temperature controllable by the amount of strontium (Sr) incorporated.

The nanoparticles were capped with oleic acid, and then were precipitated and dried. At ARL, we re-dispersed the nanoparticles into isopropanol to prepare TEM grids.

Figure 14 is a TEM image of the barium strontium titanate (BST) powder (KN238). As with the previously examined BaTiO₃ nanoparticles, the TEM images show high-quality, single-crystalline nanoparticles. The particles in this particular vial measured around 6–7 nm.

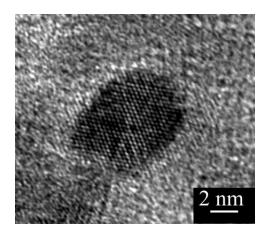


Figure 14. SEM image of an 8x8 array (one column is for ground plane contact) of $100 \times 100 \mu m$ Ti/Pt-SiO₂ capacitors.

5. Plans and Goals for Year 3, Quarter 1

In the coming quarter, we will continue to expand our nanomaterial synthesis capabilities, laser processing techniques and pyroelectric phase conversion studies, and perovskite thin-film electrical characterization efforts:

- *ICB*: This team will finalize construction of the large-scale reactor and pursue trials of continuous-flow production with automated control, further investigate the in situ stabilization of BaTiO₃ nanoparticles using PVP, and continue to provide pure and doped BaTiO₃ and Ba_{1-x}Sr_xTiO₃ nanoparticle thin films to Aerospace and ARL for laser-scripted pixelation/pyroelectric activation studies and electrical characterization of thin-film test structures.
- Aerospace: This team will continue fabrication of laser-pixelated perovskite thin-film array
 test structures for electrical analysis and IR responsiveness measurements by ARL;
 measure local PFM hysteresis curves for unexposed and laser-processed perovskite thin
 films to extract piezoelectric constants and assess uniformity of phase conversion and
 intrinsic/residual stresses in the IR test structures; and explore the laser scripted processing
 of the IR absorbing overlayer to induce patterned pyroelectric phase conversion of the
 underlying perovskite thin film.
- *ARL*: This team will modify the IR nanostructures that comprise the absorbing layer to shift absorption into the thermal imaging region (3–12 μm) and optimize the absorption strength and integrate variable temperature sample mount into electrical measurement system for frequency and temperature dependent capacitance/conductance studies on native and laser-activated BaTiO₃ and Ba_{1-x}Sr_xTiO₃ thin-film test structures.

6. Metrics for Year 2 Quarter 4

6.1 Publications

1. Niesz, K.; Morse, D. E. Sonication-accelerated Catalytic Synthesis of Oxide Nanoparticles. *Nano Today* **2010**, *5*, 99–105.

6.2 Conferences and Symposia

- 1. Livingston, F. E.; Sarney, W. L.; Niesz, K.; Morse, D. E. Laser Direct-write Activation of Perovskite Nanoparticle Films for Thermal Detector Applications. Presented Poster at the *National Defense Industrial Association (NDIA) 11th Annual Science & Engineering Technology Conference/DoD Tech. Exposition*, Charleston, SC, Apr. 12–15, 2010.
- 2. Niesz, K.; Reji, C.; Vargas, R. C.; Neilson, J.; Ould Ely, T.; Livingston, F. E.; Sarney, W. L.; Morse, D. E. Fabrication of Simple and Complex Oxide Nanoparticles by Sonication Assisted Vapor Diffusion Catalysis: Synthesis, Characterization and Applications. Presented poster at the *239th ACS National Meeting and Exposition*, San Francisco, Mar. 21, 2010.
- 3. Livingston, F. E.; Sarney, W. L.; Niesz, K.; Little, J. W.; Olver, K. A.; Morse, D. E. Laser Tailoring of Bio-inspired Thin-films for Improved Sensitivity, Low-cost Uncooled IR Detector FPAs. Presented poster at the *2010 Institute for Collaborative Biotechnologies* (ICB) Army-Industry Collaboration Conference, UC Santa Barbara, CA, Mar. 3–4, 2010.

List of Symbols, Abbreviations, and Acronyms

AFM atomic force microscopy

ARL U.S. Army Research Laboratory

Au gold

BaTiO₃ barium titanium oxide

BST barium strontium titanate

BSTO barium strontium titanium oxide

CAD computer-assisted design

CAM computer aided manufacturing

Ce cerium

CF₄ carbon tetrafluoride

FE ferroelectric

FWHM full width at half maximum

ICB Institute for Collaborative Biotechnologies

IR infrared

IR&D Independent Research and Development

nFE nonferroelectric

PDP Product and Development Program

PFM piezoelectric force microscopy

PVP polyvinylpyrrolidone

ROIC readout integrated circuit

Si silicon

SiO₂ silicon dioxide

Sr strontium

TEM transmission electron microscope

Ti/Pt titanium platinum

UV ultraviolet

Y2Q4 year two, quarter four

NO. OF COPIES ORGANIZATION

1 ADMNSTR ELEC DEFNS TECHL INFO CTR ATTN DTIC OCP 8725 JOHN J KINGMAN RD STE 0944 FT BELVOIR VA 22060-6218

- 1 CD OFC OF THE SECY OF DEFNS ATTN ODDRE (R&AT) THE PENTAGON WASHINGTON DC 20301-3080
 - 1 US ARMY RSRCH DEV AND ENGRG CMND
 ARMAMENT RSRCH DEV & ENGRG CTR
 ARMAMENT ENGRG & TECHNLGY CTR
 ATTN AMSRD AAR AEF T J MATTS BLDG 305
 ABERDEEN PROVING GROUND MD 21005-5001
 - 1 US ARMY INFO SYS ENGRG CMND ATTN AMSEL IE TD A RIVERA FT HUACHUCA AZ 85613-5300
 - 1 COMMANDER
 US ARMY RDECOM
 ATTN AMSRD AMR
 W C MCCORKLE
 5400 FOWLER RD
 REDSTONE ARSENAL AL 35898-5000
 - 1 US GOVERNMENT PRINT OFF DEPOSITORY RECEIVING SECTION ATTN MAIL STOP IDAD J TATE 732 NORTH CAPITOL ST NW WASHINGTON DC 20402
 - 2 INSTITUTE FOR COLLABORATIVE BIOTECHNOLOGIES UNIVERSITY OF CALIFORNIA, SANTA BARBARA ATTN D MORSE ATTN K NIESZ SANTA BARBARA CA 93106-5100
 - 1 THE AEROSPACE CORPORATION
 MICRO/NANOTECHNOLOGY
 DEPARTMENT
 SPACE MATERIALS LABORATORY
 ATTN F LIVINGSTON
 2350 E EL SEGUNDO BLVD
 EL SEGUNDO CA 90245

NO. OF COPIES ORGANIZATION

6 US ARMY RSRCH LAB
ATTN IMNE ALC HRR
MAIL & RECORDS MGMT
ATTN RDRL CIO LL TECHL LIB
ATTN RDRL CIO MT TECHL PUB
ATTN RDRL SEE I J LITTLE
ATTN RDRL SEE I K OLVER
ATTN RDRL SEE I W SARNEY
ADELPHI MD 20783-1197

TOTAL: 15 (1 ELEC, 1 CD, 13 HCS)

INTENTIONALLY LEFT BLANK.